Special Issue

Fault Detection and State Estimation in Automatic Control

Message from the Guest Editors

This Special Issue aims to focus on intelligent control, intelligent modeling, computational intelligence, artificial intelligence, machine learning, and fault detection. This fits the scope of *Applied Sciences* as the practical applications of fault detection and machine learning are incredibly extensive and important. In this Special Issue, original research articles and reviews are welcome. Research areas may include (but are not limited to) the following:

- Design and application of fault detection algorithms;
- Design and application of state estimation methods;
- Design and application of machine learning algorithms;
- Automatic control system characteristics analysis;
- Design and application of intelligent control systems.

Guest Editors

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Prof. Dr. Xiongbo Wan

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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